



National Institute of Standards & Technology

Certificate

Standard Reference Material[®] 2034

Holmium Oxide Solution Wavelength Standard from 240 nm to 650 nm

Series No.: 01

This Standard Reference Material (SRM) is a certified transfer standard intended for the verification and calibration of the wavelength scale of ultraviolet and visible absorption spectrophotometers having nominal spectral bandwidths not exceeding 3 nm. SRM 2034 is certified for the wavelength location of minimum transmittance for 14 bands in the spectral range from 240 nm to 650 nm and at six spectral bandwidths from 0.1 nm to 3 nm.

SRM 2034 is an aqueous solution containing 4 % (mass fraction) holmium oxide (Ho_2O_3) in 10 % (volume fraction) perchloric acid (HClO_4). The solution is contained in a flame-sealed, nonfluorescent, fused silica cuvette of optical quality (parallel to ~ 0.9 mrad and flat to ~ 1 μm). A protective cap is glued over the fused end of the cuvette. The square-bottomed (12.5 mm \times 12.5 mm) cuvette has a nominal pathlength of 10 mm and fits in the sample compartment of most conventional absorption spectrophotometers.

CAUTION: SRM 2034 is a perchloric acid solution of holmium oxide. Each SRM 2034 cuvette has been individually vacuum-tested for leaks. If a leak in the cuvette should develop or if the cuvette is accidentally broken, carefully treat the spill immediately with copious amounts of water. The remedial action described in the accompanying MSDS should be undertaken.

Certified Values: The certified wavelengths of minimum transmittance for 14 bands from 240 nm to 650 nm, and for six spectral bandwidths from 0.1 nm to 3.0 nm, are given in Table 1. These certified values apply to previously issued series of SRM 2034 for a period of 10 years from the production year indicated by the series number. The transmittance spectrum of SRM 2034, referenced to air, for a 1 nm spectral bandwidth is illustrated in Figure 1 of this Certificate.

Expiration of Certification: The certification of this SRM is valid, within the measurement uncertainties specified, until **31 December 2011**, provided the SRM is used in accordance with the instructions given in this certificate. However, the certification will be nullified if the SRM is damaged, contaminated, or modified.

Maintenance of SRM Certification: NIST will monitor this SRM over the period of its certification. If substantive changes occur that affect the certification before the expiration of this certificate, NIST will notify the purchaser. Return of the attached registration card will facilitate notification.

The overall direction and coordination of technical measurements leading to certification were performed by J.C. Travis and G.W. Kramer of the NIST Analytical Chemistry Division.

The production and certification of this SRM were performed by J.C. Travis, D.L. Duewer, and M.V. Smith of the NIST Analytical Chemistry Division with the assistance of M.D. Maley of the NIST Analytical Chemistry Division.

Statistical consultation for this SRM was provided by H-k. Liu of the NIST Statistical Engineering Division.

The vacuum testing and flame sealing of the fused-silica cuvettes for this SRM were performed by J.R. Anderson of the NIST Fabrication Technology Division.

The support aspects involved in the issuance of this SRM were coordinated through the NIST Standard Reference Materials Program by J.W.L. Thomas.

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Table 1. SRM 2034 Certified Wavelengths (nm) of Minimum Transmittance and Uncertainties^a for 14 Bands at Six Spectral Bandwidths, Referenced to Air

Band No.	0.1 nm	0.25 nm	0.5 nm	1 nm	2 nm	3 nm
1	240.99 ± 0.23	240.97 ± 0.22	241.01 ± 0.22	241.13 ± 0.21	241.08 ± 0.27	240.90 ± 0.33
2	249.83 ± 0.30	249.78 ± 0.26	249.79 ± 0.26	249.87 ± 0.21	249.98 ± 0.33	249.90 ± 0.45
3	278.15 ± 0.23	278.14 ± 0.22	278.13 ± 0.22	278.10 ± 0.20	278.03 ± 0.22	278.03 ± 0.23
4	287.01 ± 0.22	287.00 ± 0.24	287.01 ± 0.24	287.18 ± 0.27	287.47 ± 0.34	287.47 ± 0.40
5	333.47 ± 0.21	333.44 ± 0.21	333.43 ± 0.21	333.44 ± 0.21	333.40 ± 0.27	333.32 ± 0.34
6	345.55 ± 0.36	345.55 ± 0.28	345.52 ± 0.28	345.47 ± 0.20	345.49 ± 0.20	345.49 ± 0.21
7	361.36 ± 0.25	361.35 ± 0.22	361.33 ± 0.22	361.31 ± 0.18	361.16 ± 0.20	361.04 ± 0.22
8	385.45 ± 0.25	385.42 ± 0.22	385.50 ± 0.22	385.66 ± 0.20	385.86 ± 0.22	386.01 ± 0.24
9	416.07 ± 0.22	416.07 ± 0.22	416.09 ± 0.22	416.28 ± 0.21	416.62 ± 0.19	416.84 ± 0.17
10	----- ^b	----- ^b	----- ^b	451.30 ± 0.31	451.30 ± 0.24	451.24 ± 0.17
11	467.82 ± 0.19	467.82 ± 0.17	467.80 ± 0.17	467.83 ± 0.16	467.94 ± 0.17	468.07 ± 0.18
12	485.28 ± 0.25	485.28 ± 0.23	485.27 ± 0.23	485.29 ± 0.21	485.33 ± 0.22	485.21 ± 0.23
13	536.54 ± 0.28	536.53 ± 0.26	536.54 ± 0.26	536.64 ± 0.24	536.97 ± 0.22	537.19 ± 0.19
14	640.51 ± 0.27	640.49 ± 0.24	640.49 ± 0.24	640.52 ± 0.20	640.84 ± 0.24	641.05 ± 0.28

^a The uncertainties represent U_{95} , the expanded uncertainty calculated in accordance with Reference [1].

^b The wavelengths for the three narrowest spectral bandwidths for Band No. 10 are not given because this band resolves into two transmittance minima for spectral bandwidths of nominally less than 1 nm.

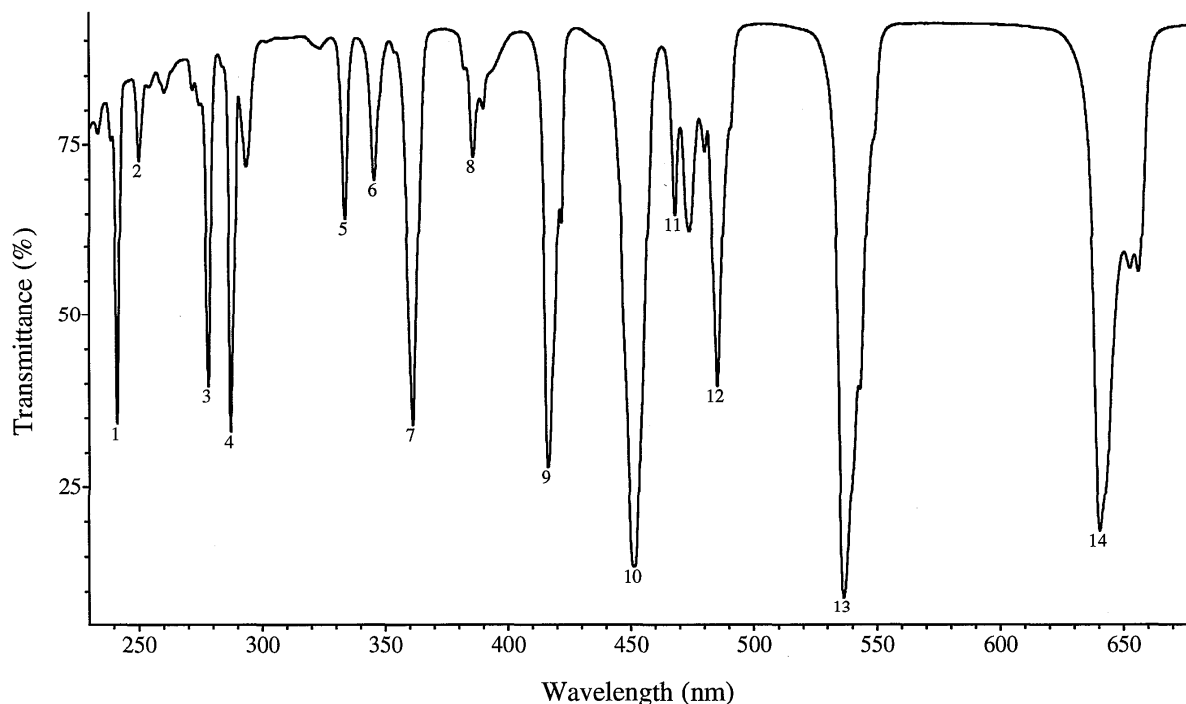


Figure 1. Spectral transmittance at 1 nm spectral bandpass of a 4 % solution of holmium oxide in 10 % perchloric acid solution.

Certification Uncertainty: The uncertainties for SRM 2034 have been revised upward from previous estimates based upon ongoing comparison measurements with cooperating laboratories from several national metrology institutes. The expanded uncertainty, U_{95} , for each of the wavelength values given in Table 1 is determined from the appropriate combination of component standard uncertainties (i.e., estimated standard deviations) with a coverage factor based on the Student's t -distribution. The expanded uncertainty defines an interval within which the unknown value of the band minimum wavelength can be asserted to lie with a level of confidence of approximately 95 % [1]. Components of the measurement uncertainty include: reproducibility, the calibration of the wavelength scale of different spectrophotometers against atomic spectral lines, and the estimation of absorption band minima. Possible wavelength shifts due to temperature and concentration of the solution have been shown to be negligible.

Production and Certification Procedure: Specific details concerning the materials, instrumentation, and methods used in the certification of SRM 2034 are given in References [2] and [3]. NBS Special Publication 260-102 [2] discusses the influence of temperature, as well as the purity and concentration of the holmium oxide solution, on the certified wavelengths. Reference [2] also describes the procedures used for assessment of the wavelengths of minimum transmittance and calibration of the wavelength scale of the spectrophotometer used for the certification.

Storage and Handling: Proper handling and storage of SRM 2034 is essential to maintain the integrity of the certified wavelength values given in Table 1. If the user determines at any time that this SRM has been exposed to adverse conditions that could affect the chemical stability of the solution, *discontinue use of the SRM and dispose of it properly.*

To maintain the integrity of SRM 2034, the cuvette should be handled only by the capped end or by its opposing frosted sides. Avoid unnecessary stress to the glue seal of the cuvette cap. While not in use, SRM 2034 should be stored in the container provided at a temperature between 20 °C and 30 °C.

INSTRUCTIONS FOR USE

Carefully insert SRM 2034 into the sample beam of the spectrophotometer being tested and leave the reference beam empty. Scan the desired bands to measure their locations of minimum transmittance for known spectral bandwidth conditions. Take all measurements at a temperature of 25 °C ± 5 °C.

Wavelength Scale Verification: Compare the measured wavelength of a specific band's minimum transmittance to its certified wavelength in Table 1, for the spectral bandwidth most representative of the spectrophotometer being tested. The absolute value of the difference between the measured and certified value for each band should not exceed the certification uncertainties given in Table 1 by more than the wavelength accuracy specified for the instrument under test or the desired application. In the event that verification of the native wavelength scale is not obtained over the wavelength range, an external calibration curve may be constructed.

Wavelength Scale Calibration: Any significant biases indicated by subtracting the certified wavelengths from the corresponding measured wavelengths may be plotted as a function of the wavelengths (either measured or certified, since the difference is small). This plot, with a smooth line drawn through the fourteen measured bias points, represents a bias correction wavelength calibration for the instrument under test. To find the true wavelength corresponding to an indicated wavelength, subtract the bias corresponding to the wavelength from the indicated wavelength. To find the indicated wavelength corresponding to a desired true wavelength, add the bias value corresponding to the wavelength to the true wavelength.

REFERENCES

- [1] *Guide to the Expression of Uncertainty in Measurement*, ISBN 92-67-10188-9, 1st Ed., ISO, Geneva, Switzerland, (1993); see also Taylor, B.N. and Kuyatt, C.E., "Guidelines for Evaluating and Expressing the Uncertainty of NIST Measurement Results," NIST Technical Note 1297, U.S. Government Printing Office, Washington, DC, (1994); available at <http://physics.nist.gov/Pubs/>.
- [2] Weidner, V.R., Mavrodineanu, R., Mielenz, K.D., Velapoldi, R.A., Eckerle, K.L., and Adams, B., "Holmium Oxide Solution Wavelength Standard from 240 to 640 nm - SRM 2034," NBS Special Publication 260-102, (1986).
- [3] Weidner, V.R., Mavrodineanu, R., Mielenz, K.D., Velapoldi, R.A., Eckerle, K.L., and Adams, B., "Spectral Transmittance Characteristics of Holmium Oxide in Perchloric Acid," J. Res. Natl. Bur. Stds., **Vol. 90**, No. 2, pp. 115-125, (1985).

Certificate Revision History: 04 February 2002 (Update Table I); 28 November 2001 (Original certificate date).

Users of this SRM should ensure that the certificate in their possession is current. This can be accomplished by contacting the SRM Program at: telephone (301) 975-6776; fax (301) 926-4751; e-mail srminfo@nist.gov; or via the Internet <http://www.nist.gov/srm>.